

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant:	Bruce et al.	Examiner:	Turner, S.
Serial No.:	09/386,112	Group Art Unit:	2877
Filed:	August 30, 1999	Docket No.:	AMDA.261PA
Title:	DUAL-DIFFERENTIAL INTERFEROMETRY FOR SILICON DEVICE DAMAGE DETECTION		

CERTIFICATE UNDER 37 CFR 1.8: The undersigned hereby certifies that this correspondence and the papers, as described hereinabove, are being transmitted via facsimile only-Formal Entry, to the attention of Examiner S. Turner, Assistant Commissioner for Patents, Washington, D.C. 20231, on October 28, 2002.

By: Eric J. Curtin

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Eric J. Curtin

OFFICE ACTION RESPONSE AND AMENDMENT

BOX AF
Assistant Commissioner for Patents
Washington, D.C. 20231

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OCT 28 2002

Dear Sir:

TECHNOLOGY CENTER 2800

In response to the Office Action dated August 27, 2002, please consider the following remarks.

Remarks

Favorable reconsideration of this application is requested in view of the following remarks. For the reasons set forth below, Applicant respectfully submits that the claimed invention is allowable over the cited references.

The Office Action dated August 27, 2002 indicated that claims 1-16 stand rejected under Section 112(1); claims 1-16 stand rejected under Section 112(2); and claims 1, 2, 7, and 9-15 stand rejected under Section 103(a) as being unpatentable over *Marx et al.* (U.S. Patent No. 5,880,838).